

(Supplemental)

# Oxide film properties using OH radicals generated by water vapor mixed pure ozone gas as ALD oxidant

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PO-ALD merit items	Memo
High reactivity	Requires multi-step ozone collision reaction with precursor
Long life time	Decreased reaction frequency with O <sub>2</sub> molecules
High active species concentration	High concentrated Ozone gas by liquefaction (>80 vol.%)
High purity	NO <sub>x</sub> and heavy metal contaminations free
High growth rate	Highly efficient oxidizing gas diffusion at low pressure in the ALD chamber
Film thickness distribution	
Reduction of O <sub>2</sub> gas consumption	On-demand O <sub>3</sub> gas supply system

Table 1. Pure ozone generator and merits of pure ozone ALD (PO-ALD).

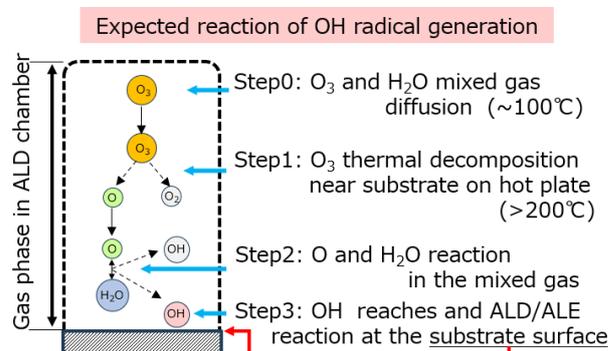


Figure 2. Schematic chemical reaction of OH radical generated reaction in ALD chamber.

This work (expected)

Film qualities/ Oxidation sources	Pure ozone +H <sub>2</sub> O vapor	O <sub>2</sub> plasma	Pure ozone (PO)	Ozonizer ozone
Electric properties (Ex. dielectric)	Best	Best	Good	OK
Step coverage	Best	Bad	Best	OK
Productivity (Batch processing)	Best	Bad	Best	OK

Table 2. Comparison of film properties using some ALD oxidation sources.

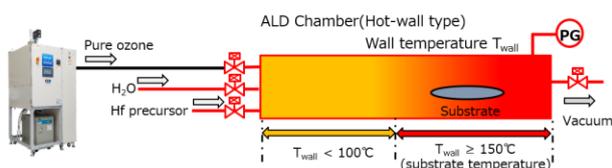


Figure 1. Schematic ALD chamber and gas piping systems.

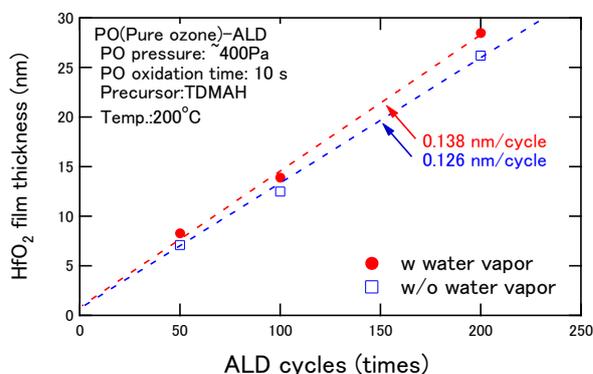


Figure 3. Relation between the number of ALD cycles and HfO<sub>2</sub> film thickness.